Sample Results Summary Sheet
Please return this form to the Curator for each allocated Sample

Sample ID: RA-QD02-0180
PI: Masayuki Uesugi

Type and date of analysis performed:
FIB sectioning (Jul. 16, 2013 and Nov. 3, 2014)

Elements or phases identified: (Mg, Si, olivine, pyroxene, aromatic carbon, etc.)
N/A

Contaminant phases identified: (Al, SUS, carbon particles, etc.)
N/A

Sample handling: (e.g. exposed in atmosphere, embedded in resin, polished, sliced by FIB or UMT)
Pressed on In plate (3mm diameter and 0.3mm thick) by Sapphire glass
Sectioned by Focused Ion Beam (FIB) (3 ultra-thin sections were extracted).

State of sample pre-analysis:
N2 hold.

State of sample post-analysis:
RA-QD02-0180:pressed on In plate, partially sectioned by FIB, damaged by Ga beam, N2 hold in sample holder
RA-QD02-0180-01: UTS by FIB
RA-QD02-0180-02: UTS by FIB
RA-QD02-0180-03: UTS by FIB

Analysis data Notes: (summary of the attached analysis data and/or images)

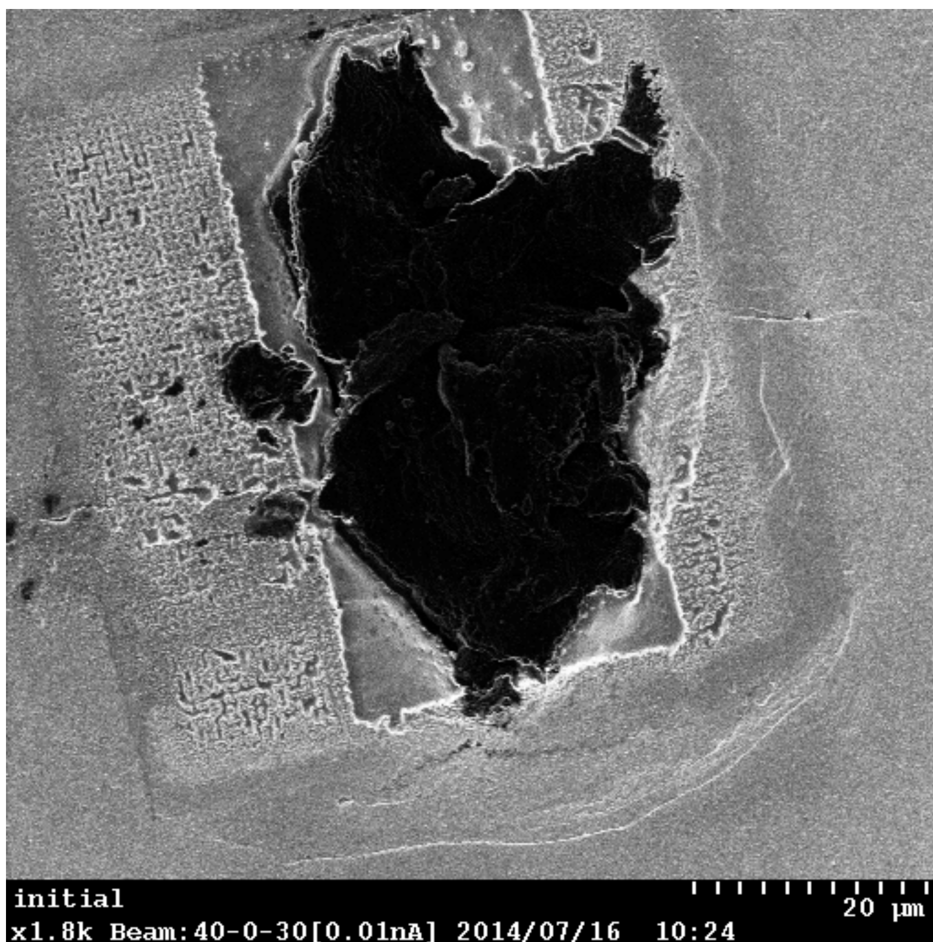

Fig.1 Scanning Ion microscope (SIM) image of RA-QD02-0180 after pressing on In plate

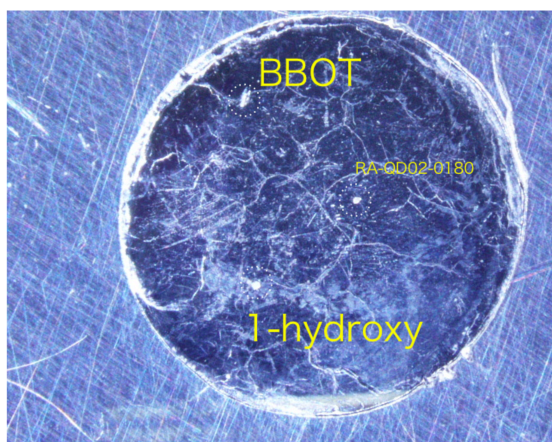

Fig. 2 Whole view of In plate. Standards for NanoSIMS analysis were also pressed on the In plate. The In plate was pressed and fixed on a half-inch Al holder .

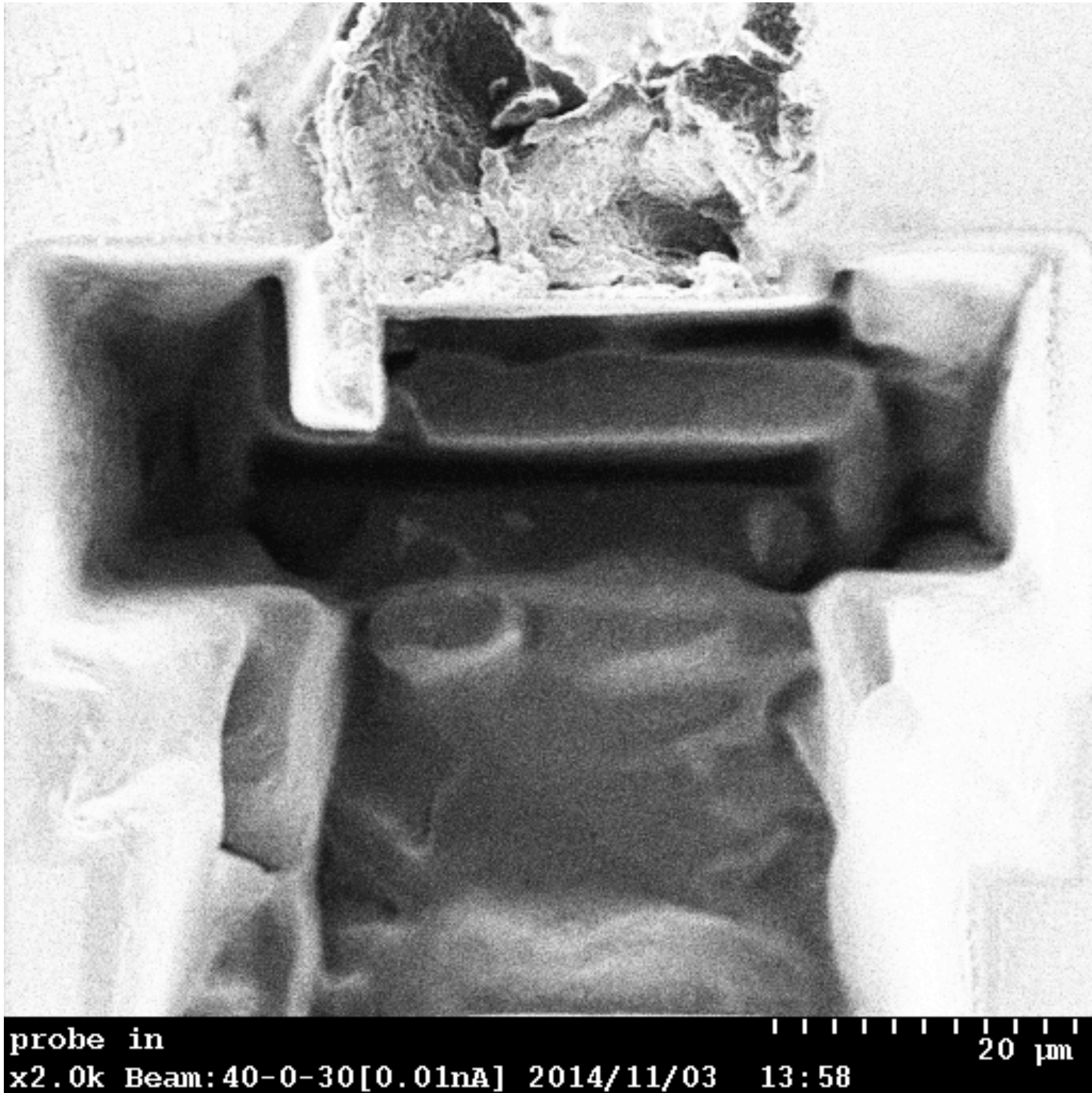

Fig. 3 SIM image of extraction of RA-QD02-0180-03 by FIB fabrication (final condition of RA-QD02-0180).